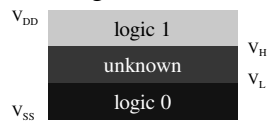


Logic levels

- Solid logic 0/1 defined by V_{SS}/V_{DD} .
- Inner bounds of logic values V_L/V_H are not directly determined by circuit properties, as in some other logic families.

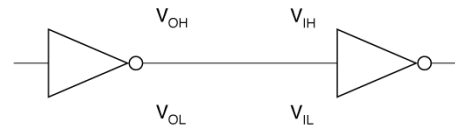


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Logic level matching

- Levels at output of one gate must be sufficient to drive next gate.

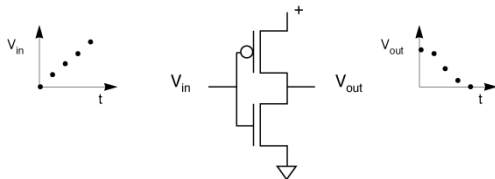


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Transfer characteristics

- Transfer curve shows static input/output relationship—hold input voltage, measure output voltage.

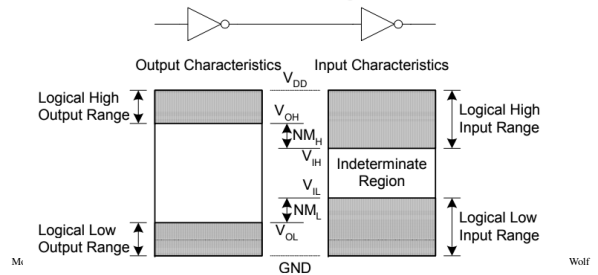


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Noise Margins

How much noise can a gate input see before it does not recognize the input?



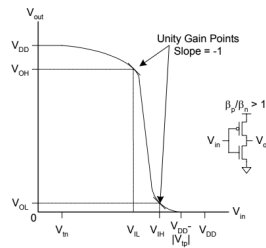
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Inverter transfer curve

To maximize noise margins, select logic levels at

- unity gain point of DC transfer characteristic



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Logic thresholds

- Choose threshold voltages at points where slope of transfer curve = -1.
- Inverter has a high gain between V_{IL} and V_{IH} points, low gain at outer regions of transfer curve.
- Note that logic 0 and 1 regions are not equal sized—in this case, high pullup resistance leads to smaller logic 1 range.

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Noise margin

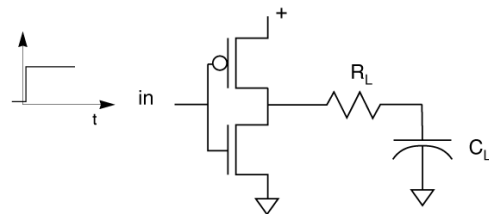
- Noise margin = voltage difference between output of one gate and input of next. Noise must exceed noise margin to make second gate produce wrong output.

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Delay

- Assume ideal input (step), RC load.



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Delay assumptions

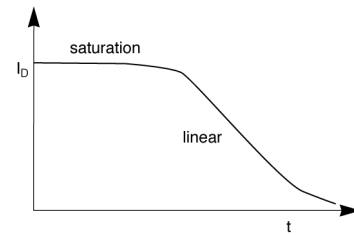
- Assume that only one transistor is on at a time. This gives two cases:
 - rise time, pullup on;
 - fall time, pullup off.
- Assume resistor model for transistor. Ignores saturation region and mischaracterizes linear region, but results are acceptable.

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Current through transistor

- Transistor starts in saturation region, then moves to linear region.

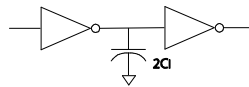


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Capacitive load

- Most capacitance comes from the next gate.
- Load is measured or analyzed by Spice.
- C_L : load presented by one minimum-size transistor.



$$C_L = \sum (W/L)_i C_1$$

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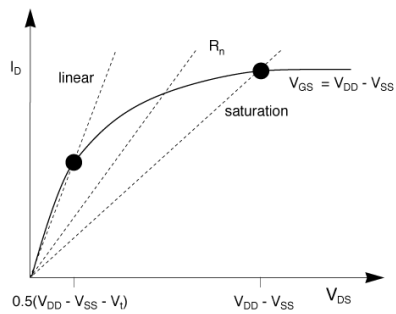
Resistive model for transistor

- Average V/I at two voltages:
 - maximum output voltage
 - middle of linear region
- Voltage is V_{ds} , current is given I_d at that drain voltage. Step input means that $V_{gs} = V_{DD}$ always.

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Resistive approximation



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Ways of measuring gate delay

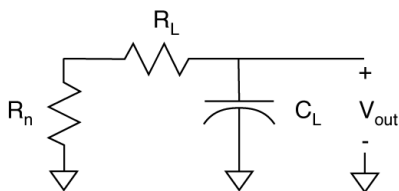
- Delay: time required for gate's output to reach 50% of final value.
- Transition time: time required for gate's output to reach 10% (logic 0) or 90% (logic 1) of final value.

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Inverter delay circuit

- Load is resistor + capacitor, driver is resistor.



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Inverter delay with τ model

- τ model: gate delay based on RC time constant τ .
- $V_{out}(t) = V_{DD} \exp\{-t/(R_n + R_L)/C_L\}$
- $t_f = 2.2 R C_L$
- For pullup time, use pullup resistance.

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τ model inverter delay

■ 0.5 micron process:

- $R_n = 6.47 \text{ k}\Omega$
- $C_1 = 0.89 \text{ fF}$
- $C_L = 1.78 \text{ fF}$

■ So

- $t_d = 0.69 \times 6.47 \times 10^3 \times 1.78 \times 10^{-15} = 7.8 \text{ ps.}$
- $t_f = 2.2 \times 6.47 \times 10^3 \times 1.78 \times 10^{-15} = 26.4 \text{ ps.}$